

IAP20 Rec'd PCT/PTO 31 JAN 2006 SHEET 1 OF 1

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| FORM PTO - 1449 | | | | ATTORNEY DOCKET NO.: MIT-166 | | | | | |
| INFORMATION DISCLOSURE STATEMENT | | | | APPLICANT(S): Liu <i>et al.</i> | | | | | |
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| U.S. PATENT DOCUMENTS | | | | | | | | | |
| EXAM. INIT. | | DOCUMENT NUMBER | DATE | NAME | CLASS | SUB CLASS | FILING DATE IF APPROPRIATE | | |
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| FOREIGN PATENT DOCUMENTS | | | | | | | | | |
| EXAM. INIT. | | DOCUMENT NUMBER | DATE | COUNTRY CODE | CLASS | SUB CLASS | FILING DATE | ABSTRACT ONLY | ENGLISH LANG (Y/N) |
| /JL/ | B1 | WO 03/105189 | 12/18/2003 | WO | | | | | |
| /JL/ | B2 | WO 04/001857 | 12/31/2003 | WO | | | | | |
| OTHER DOCUMENTS: (Including Author, Title, Date, Relevant Pages, Place of Publication) | | | | | | | | | |
| /JL/ | C1 | Boyanov, et al., "Growth of epitaxial CoSi ₂ on SiGe (001)", <u>Journal of Applied Physics</u> , American Institute of Physics, New York, US. 86(3):1355-1362 (1999). | | | | | | | |
| /JL/ | C2 | Buchal et al., "Ultrafast Si-based MSM mesa photodetectors with optical waveguide connection," <u>Materials Science in Semiconductor Processing</u> , 3:399-403 (2000). XP001205581 | | | | | | | |
| /JL/ | C3 | Steege et al., "Silicide-induced stress in Si: origin and consequences for MOS technologies," <u>Materials Science and Engineering R: Reports</u> , Elsevier Sequoia S.A., Lausanne, CH. 38(1):1-53 (2002). | | | | | | | |
| /JL/ | C4 | Yodo et al., "Influences of off-angle and off-direction of substrate on crystalline quality of GaAs and Ge heteroepitaxial films grown on vicinal Si (110) substrates by molecular-beam epitaxy", <u>Journal of Crystal Growth</u> , North-Holland Publishing Co., Amsterdam, NL. 209(4):724-733 (2000). XP004198396 | | | | | | | |
| /JL/ | C5 | International Search Report for PCT/US2004/024747 dated March 22, 2005. | | | | | | | |
| EXAMINER | | | | /Jonathan Langman/ | | | | | |
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